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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

QB

Applicants: Stolte, et al.
Serial No.: 09/922,115
Filed: August 3, 2001
For: WAVELENGTH MEASUREMENT ADJUSTMENT
Art Unit: 2877
Examiner: Lyons, Michael A.

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Attorney Docket: 987.0023USU

AMENDMENT AND RESPONSE

Box: Non Fee Amendment
Assistant Commissioner for Patents
Washington, D.C. 20231

Dear Sir:

In response to the Office Action dated November 20, 2002, please amend the above-noted application as follows:

IN THE SPECIFICATION

Please replace the paragraph commencing at page 3, line 15 with the following new paragraph:

B1
---A preferred embodiment of the wavemeter unit makes use of the interferometric principle, such as the Fizeau, Michelson or Fabry-Perot interferometer or uses e.g. a combination of different etalons (which can be also realized based on polarization effects) as disclosed in detail in the aforementioned EP-A- 875743. Those interferometric units generally provide a